



ACE5807B

P-Channel Enhancement Mode Field Effect Transistor

Description

The ACE5807B combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications. Standard Product ACE5807B is Pb-free.

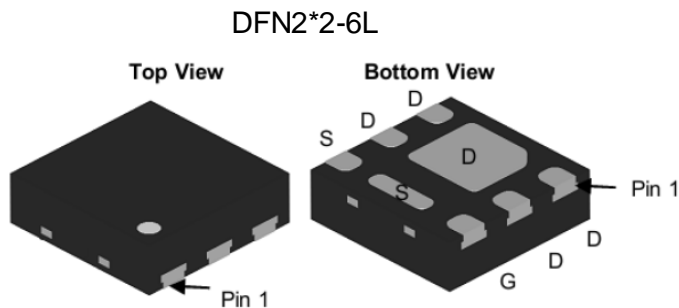
Features

- V_{DS} (V) = -12V
- I_D = -16A
- $R_{DS(ON)}$
 - < 18m Ω (V_{GS} = -4.5V)
 - < 22m Ω (V_{GS} = -2.5V)
- DFN2x2-6L Package

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit	
Drain-Source Voltage	V_{DSS}	-12	V	
Gate-Source Voltage	V_{GSS}	± 10	V	
Drain Current (Continuous)	I_D	$T_A=25^\circ\text{C}$	-16	A
		$T_A=70^\circ\text{C}$	-13	
Drain Current (Pulsed)	I_{DM}	-65	A	
Power Dissipation	P_D	$T_A=25^\circ\text{C}$	18	W
		$T_A=70^\circ\text{C}$	9	
Operating temperature / storage temperature	T_J/T_{STG}	-55~150	$^\circ\text{C}$	

Packaging Type



Ordering information

ACE5807B XX + H

- └─ Halogen - free
- └─ Pb - free
- └─ MN: DFN2*2-6L



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Electrical Characteristics

$T_A=25^{\circ}\text{C}$, unless otherwise specified.

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}, I_D=-250\mu\text{A}$	-12			V
Zero Gate Voltage Drain Current	I_{DSS1}	$V_{DS}=-12\text{V}, V_{GS}=0\text{V}$			-1	μA
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_{DS}=-250\mu\text{A}$	-0.4	-0.7	-1	V
Gate Leakage Current	I_{GSS}	$V_{GS}=\pm 8\text{V}, V_{DS}=0\text{V}$			± 100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS}=-4.5\text{V}, I_D=-6.7\text{A}$		12	18	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-6.2\text{A}$		15	22	$\text{m}\Omega$
Forward Trans Conductance	g_{FS}	$V_{DS}=-10\text{V}, I_D=-6.7\text{A}$		40		S
Diode Forward Voltage	V_{SD}	$I_{SD}=-1.6\text{A}, V_{GS}=0\text{V}$		-0.6	-1.0	V
Maximum Body-Diode Continuous Current	I_S				-16	A
Switching						
Total Gate Charge	Q_g	$V_{DS}=-6\text{V}, I_D=-10\text{A},$ $V_{GS}=-4.5\text{V}$		35	48	nC
Gate-Source Charge	Q_{gs}			5		nC
Gate-Drain Charge	Q_{gd}			10		nC
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=-10\text{V}, R_L=0.75\Omega,$ $I_D=-1\text{A}, V_{GEN}=-4.5\text{V}$ $R_G=10\Omega$		11		ns
Turn-on Rise Time	t_r			30		ns
Turn-off Delay Time	$t_{d(off)}$			30		ns
Turn-off Fall Time	t_f			10		ns
Dynamic						
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=-10\text{V},$ $f=1.0\text{MHz}$		2700		pF
Output Capacitance	C_{oss}			680		pF
Reverse Transfer Capacitance	C_{rss}			590		pF

Note:

- A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$.
- B. The Power dissipation PD is based on $R_{\theta JA}t \leq 10\text{s}$ value and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
- C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^{\circ}\text{C}$.
- D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}=150^{\circ}\text{C}$. The SOA curve provides a single pulse rating.
- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$.



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Typical Performance Characteristics

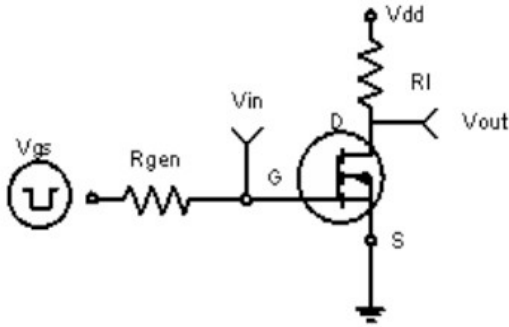


Figure 1: Switching Test Circuit

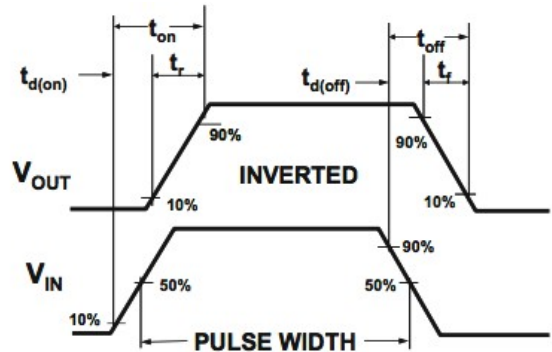


Figure 2: Switching Waveforms

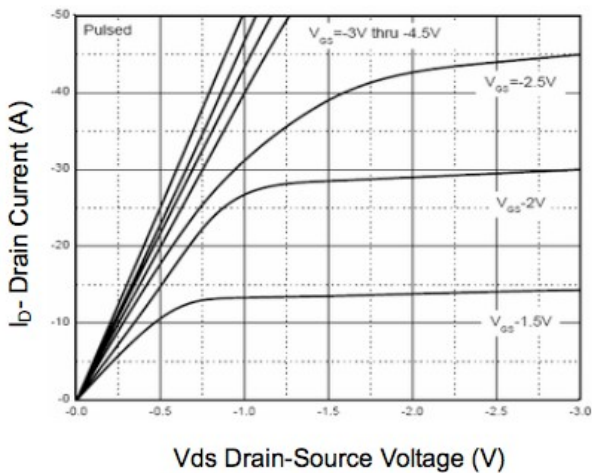


Figure 3 Output Characteristics

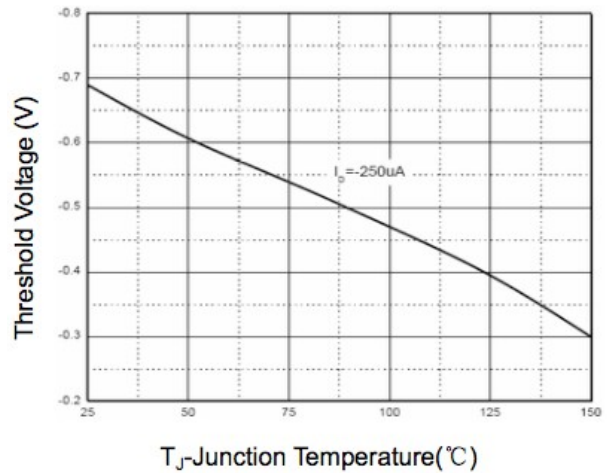


Figure 4 Drain Current

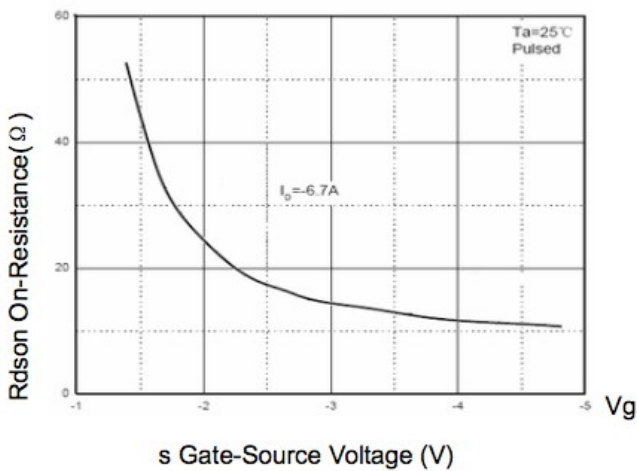


Figure 5 Rdson vs Vgs

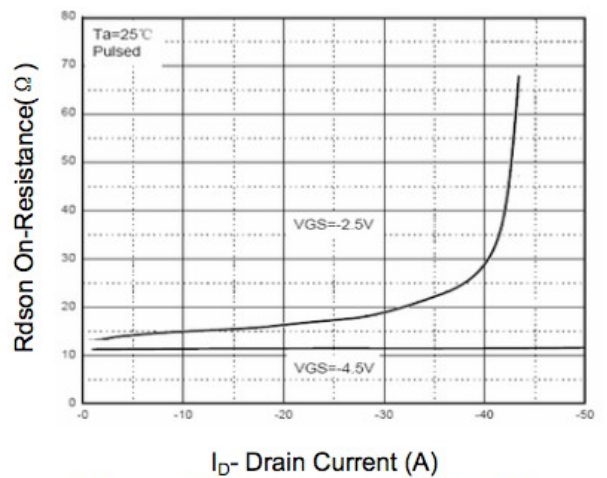
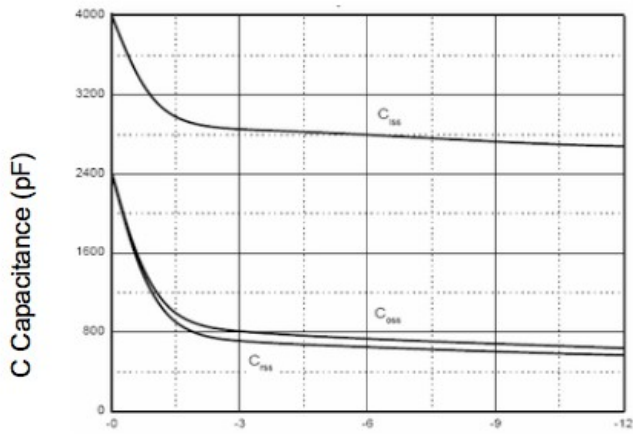
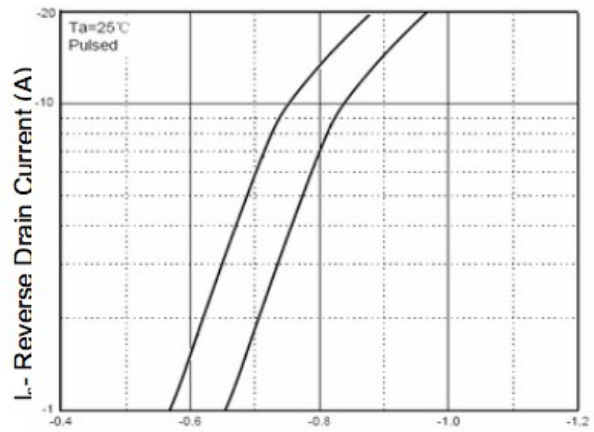


Figure 6 Drain-Source On-Resistance



Vds Drain-Source Voltage (V)
Figure 7 Capacitance vs Vds



Vsd Source-Drain Voltage (V)
Figure 8 Source- Drain Diode Forward

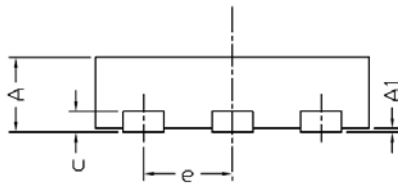
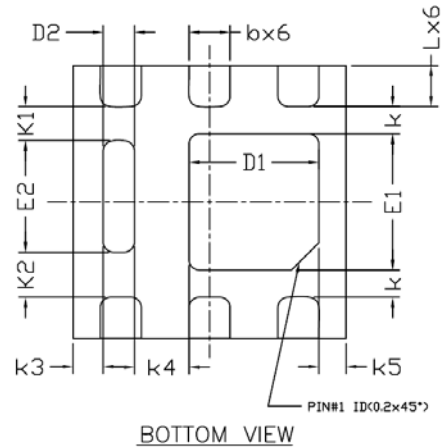
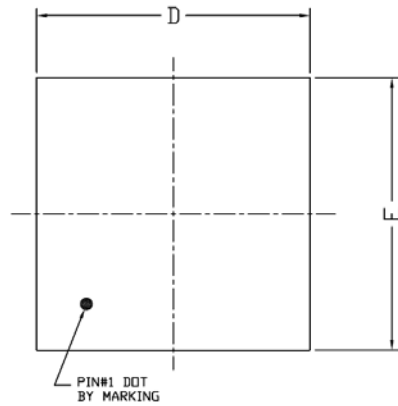


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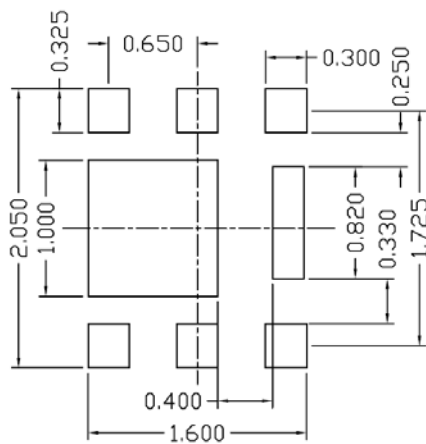
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Packing Information

DFN2*2-6



RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.50	0.55	0.60	0.020	0.022	0.024
A1	0.00	—	0.05	0.000	—	0.002
b	0.25	0.30	0.35	0.010	0.012	0.014
c	0.152 REF			0.006 REF		
D	1.90	2.00	2.10	0.075	0.079	0.083
D1	0.85	0.95	1.05	0.033	0.037	0.041
D2	0.13	0.23	0.33	0.005	0.009	0.013
E	1.90	2.00	2.10	0.075	0.079	0.083
E1	0.90	1.00	1.10	0.035	0.039	0.043
E2	0.72	0.82	0.92	0.028	0.032	0.036
e	0.65 BSC			0.026 BSC		
K	0.20 BSC			0.008 BSC		
K1	0.25 BSC			0.010 BSC		
K2	0.33 BSC			0.013 BSC		
K3	0.22 BSC			0.009 BSC		
K4	0.40 BSC			0.016 BSC		
K5	0.20 BSC			0.008 BSC		
L	0.25	0.30	0.35	0.010	0.012	0.014

NOTE

1. CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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Notes

ACE does not assume any responsibility for use as critical components in life support devices or systems without the express written approval of the president and general counsel of ACE Electronics Co., LTD. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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